

Product Summary

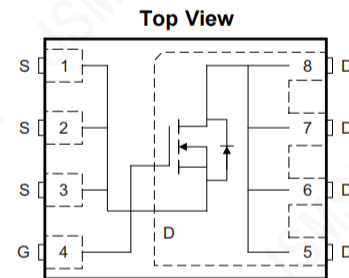
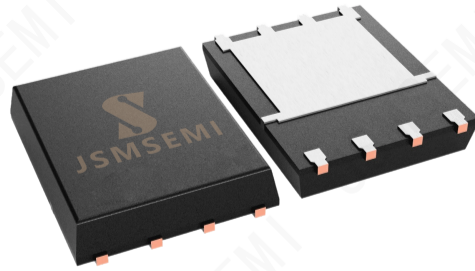
- V_{DS} 40V
- I_D 120A
- $R_{DS(ON)}$ (at $V_{GS}=10V$) <2.2m Ω
- 100% EAS Tested
- 100% ∇V_{DS} Tested

General Description

- Split gate trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$
- Moisture Sensitivity Level 1
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- Power switching application
- Uninterruptible power supply
- DC-DC convertor



Absolute Maximum Ratings (T_A= 25°C unless otherwise noted)

Symbol	Parameter	Rating	Unit	
Common Ratings				
V_{DSS}	Drain-Source Voltage	40	V	
V_{GSS}	Gate-Source Voltage	±20		
I_D^G	Continuous Drain Current	T _C =25°C	120 ^G	
		T _C =25°C	205 ^I	
		T _C =100°C	100 ^G	
I_{DM}^C	Pulsed Drain Current	550	A	
I_{DSM}	Continuous Drain Current	T _A =25°C		40
		T _A =70°C	32	
P_D^B	Power Dissipation	T _C =25°C	157	
		T _C =100°C	62	
I_S^G	Diode Continuous Forward Current	120	A	
T _{STG} , T _J	Storage Temperature Range	-55 to 150	°C	
P_{DSM}	Power Dissipation	T _A =25°C	6.2	
		T _A =70°C	4	
I_{AS}^C	Single pulsed avalanche Current	47	A	
E_{AS}^C	Single pulsed avalanche energy	L=0.3mH	331	mJ
$R_{\theta JC}$	Thermal Resistance-Junction to Case	0.8	°C/W	
$R_{\theta JA}^{AD}$	Thermal Resistance-Junction to Ambient	t≤10S		20
		Steady State		50

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V	40			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =40V, V _{GS} =0V			1	μA
		T _J =55°C			5	
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1	1.7	2.5	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =50A		2.0	2.2	mΩ
		T _J =125°C		2.25	3	
		V _{GS} =4.5V, I _D =20A		2.2	3.5	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =20A		100		S
V _{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.7	1	V
I _S	Maximum Body-Diode Continuous Current ^G				120	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =20V, f=1MHz		3200		pF
C _{oss}	Output Capacitance			1600		pF
C _{rss}	Reverse Transfer Capacitance			75		pF
R _g	Gate resistance	f=1MHz	1	2	3.1	Ω
SWITCHING PARAMETERS						
Q _g (10V)	Total Gate Charge	V _{GS} =10V, V _{DS} =20V, I _D =20A		46		nC
Q _g (4.5V)	Total Gate Charge			23		nC
Q _{gs}	Gate Source Charge			6.2		nC
Q _{gd}	Gate Drain Charge			6.5		nC
Q _{oss}	Output Charge	V _{GS} =0V, V _{DS} =20V		28		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =20V, R _L =1Ω, R _{GEN} =3Ω		12.5		ns
t _r	Turn-On Rise Time			9.5		ns
t _{D(off)}	Turn-Off DelayTime			57.5		ns
t _f	Turn-Off Fall Time			10.5		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =20A, di/dt=500A/μs		20		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =20A, di/dt=500A/μs		60		nC

A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The Power dissipation P_{DSM} is based on R_{θJA} ≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature T_{J(MAX)}=150° C.

D. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.

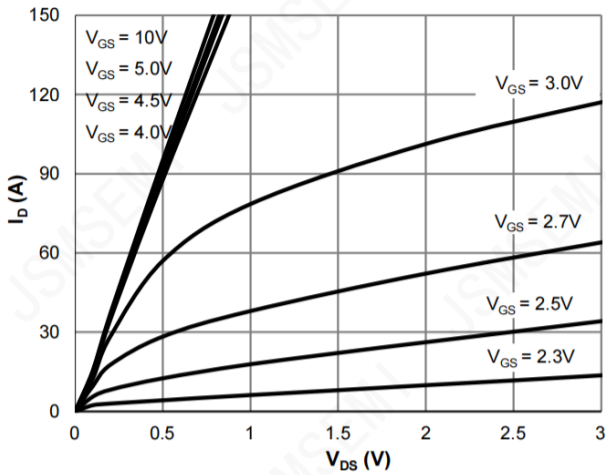
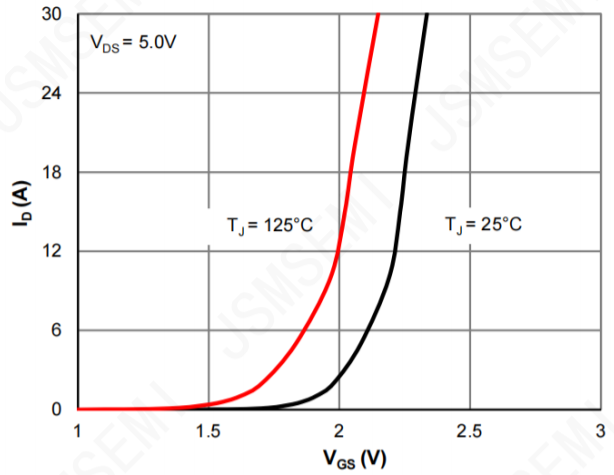
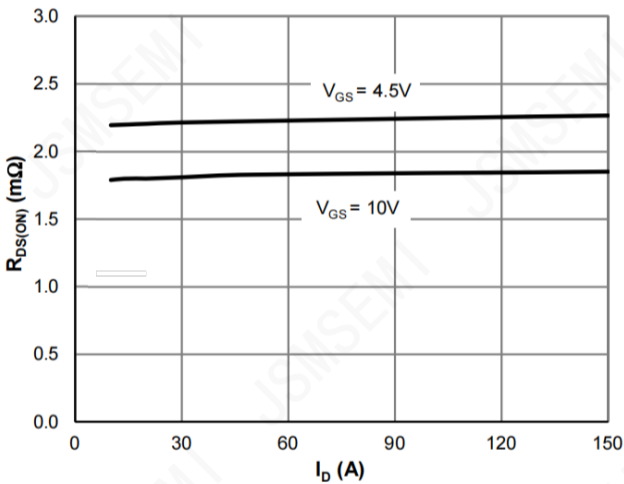
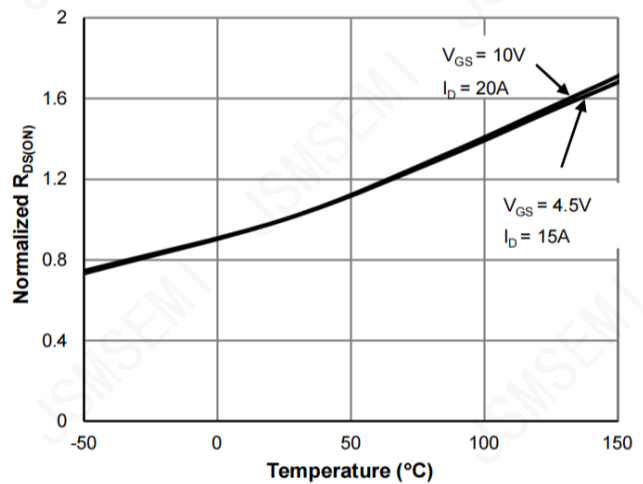
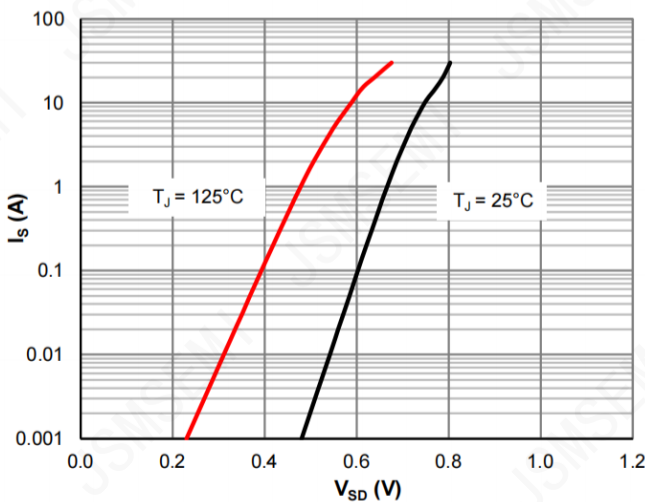
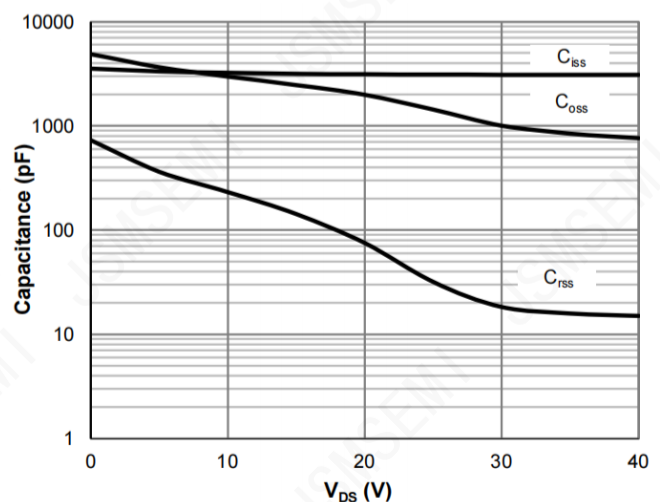
G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.

I. The maximum current rating is silicon limited

Ordering Information

Order number	Package	Marking	Operation Temperature Range	MSL Grade	Ship,Quantity	Green
BSC027N04LSGATMA1-JSM	DFN5060-8L	022N04QGL/5	-55 to 150°C	1	T&R,5000	Rohs

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: Saturation Characteristics

Figure 2: Transfer Characteristics

Figure 3: $R_{DS(ON)}$ vs. Drain Current

Figure 4: $R_{DS(ON)}$ vs. Junction Temperature

Figure 5: Body-Diode Characteristics

Figure 6: Capacitance Characteristics

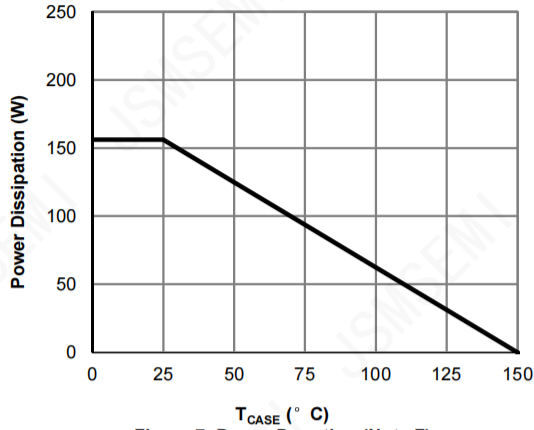
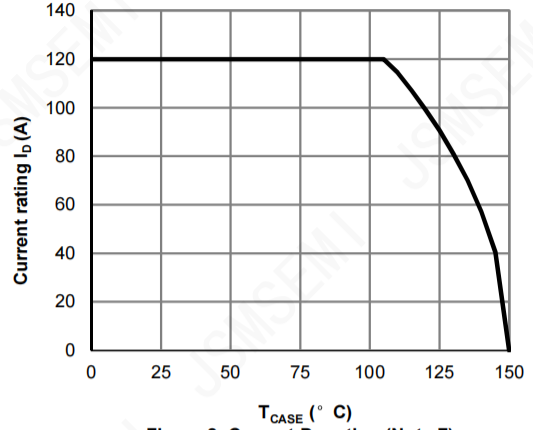
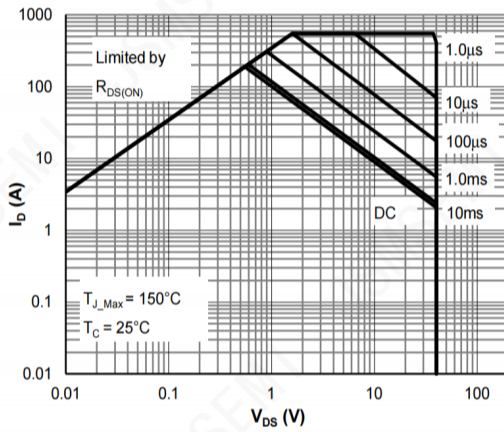
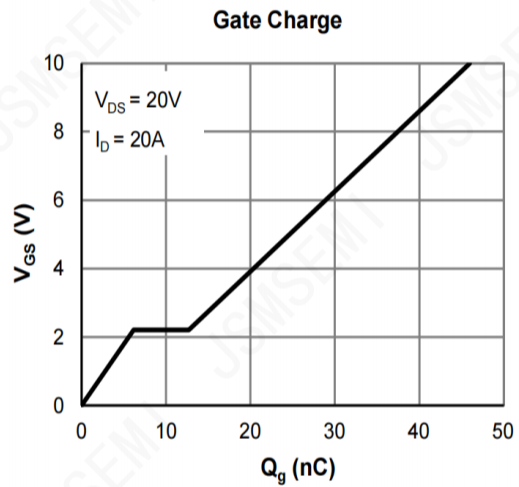
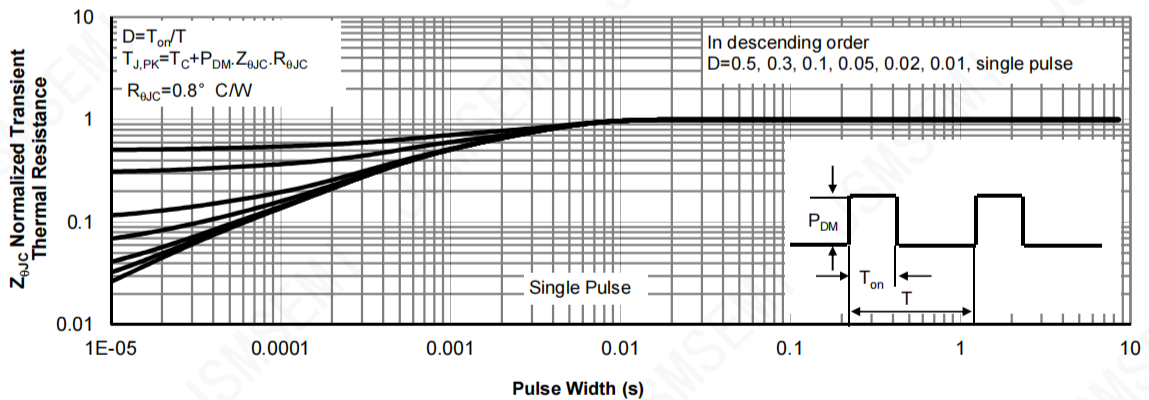
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Power De-rating (Note F)

Figure 8: Current De-rating (Note F)

Figure 9: Maximum Safe Operating Area

Figure 10: Gate Charge

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Figure A: Gate Charge Test Circuit & Waveforms

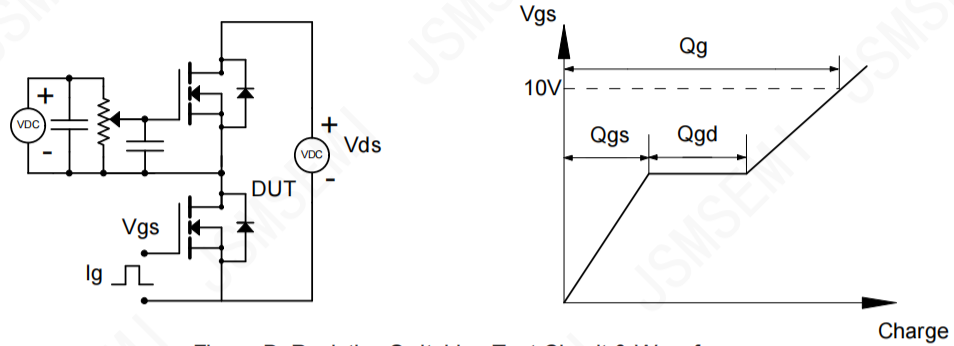


Figure B: Resistive Switching Test Circuit & Waveforms

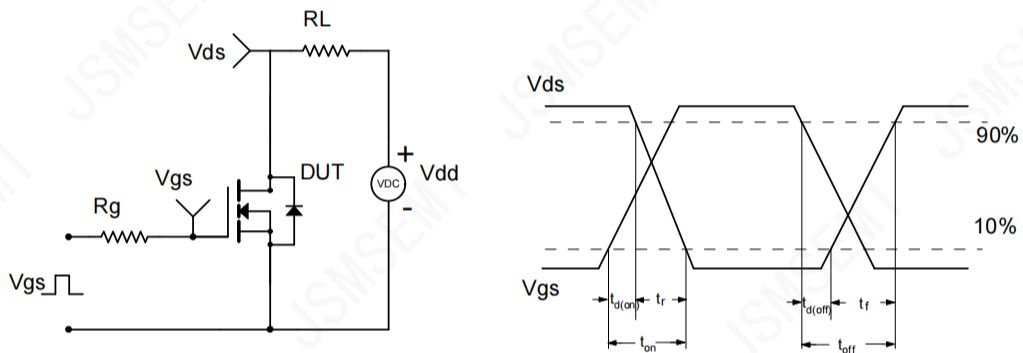


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

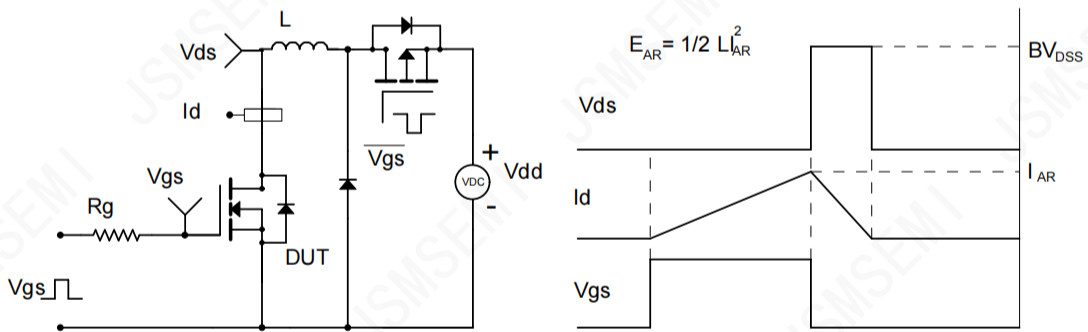
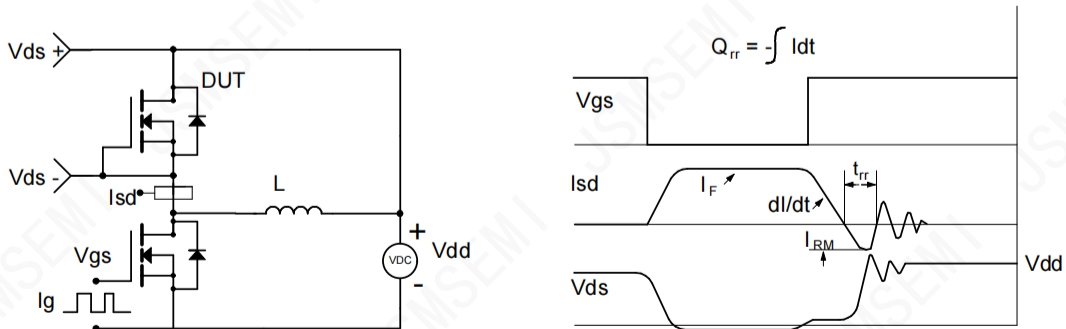
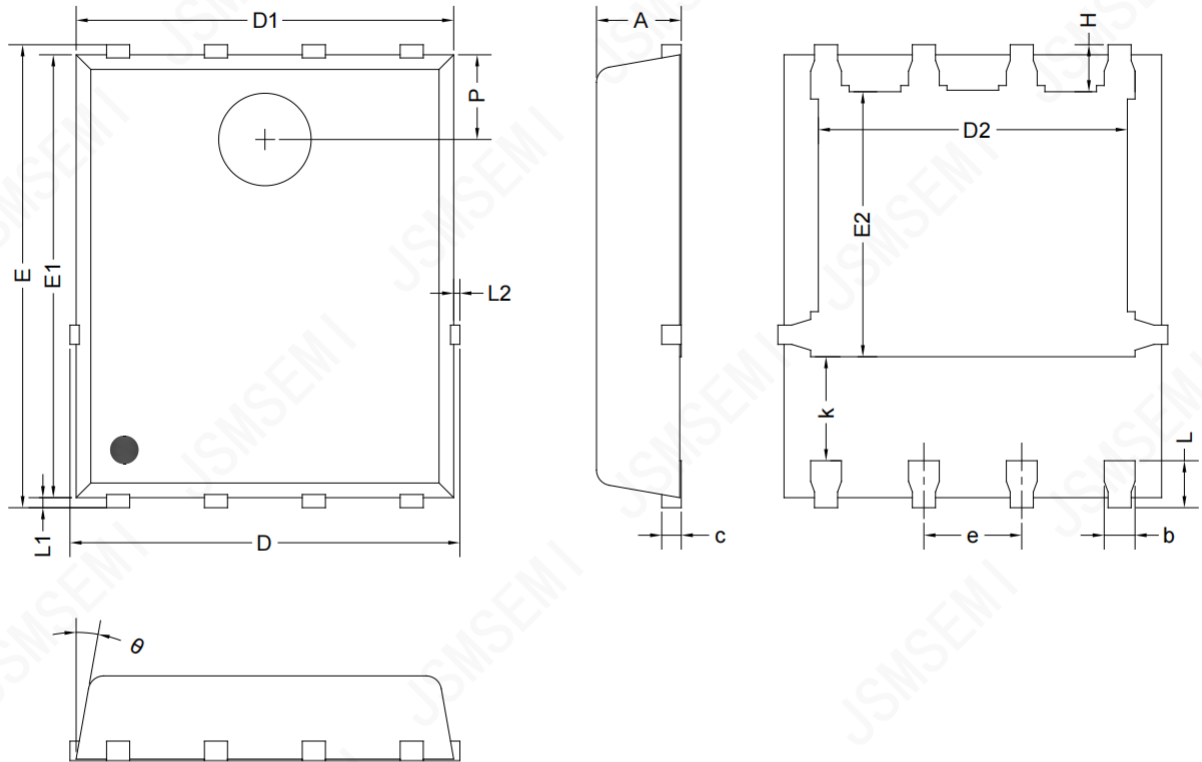


Figure D: Diode Recovery Test Circuit & Waveforms



Package Information
PDFN5060-8L


Symbol	Dimensions In Millimeters		
	MIN	NOM	MAX
A	1.000	1.100	1.200
b	0.350	0.400	0.450
c	0.210	0.250	0.340
D	4.800	-	5.100
D1	4.800	4.900	5.000
D2	3.910	4.010	4.110
E	5.900	6.000	6.100
E1	5.700	5.750	5.800
E2	3.340	3.440	3.540
e	1.270 BSC		
H	0.510	0.610	0.710
k	1.100	-	-
L	0.510	0.610	0.710
L1	0.060	0.130	0.200
L2	-	-	0.100
P	1.000	1.100	1.200
θ	8°	10°	12°

NOTE: This drawing is subject to change without notice.